BLF578

Power LDMOS transistor

Rev. 02 — 4 February 2010

Product data sheet

1. Product profile

1.1 General description

A 1200 W LDMOS power transistor for broadcast applications and industrial applications in the HF to $500 \ \text{MHz}$ band.

Table 1. Application information

Mode of operation	f	V _{DS}	PL	Gp	$\eta_{\mathbf{D}}$
	(MHz)	(V)	(W)	(dB)	(%)
CW	108	50	1000	26	75
pulsed RF	225	50	1200	24	71

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Therefore care should be taken during transport and handling.

1.2 Features

- Typical pulsed performance at frequency of 225 MHz, a supply voltage of 50 V and an I_{Dq} of 40 mA, a t_p of 100 μs with δ of 20 %:
 - ◆ Output power = 1200 W
 - ◆ Power gain = 24 dB
 - ◆ Efficiency = 71 %
- Easy power control
- Integrated ESD protection
- Excellent ruggedness
- High efficiency
- Excellent thermal stability
- Designed for broadband operation (10 MHz to 500 MHz)
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

1.3 Applications

- Industrial, scientific and medical applications
- Broadcast transmitter applications



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2. Pinning information

Table 2. Pinning

Table 2.	i iiiiiiig		
Pin	Description	Simplified outline	Graphic symbol
1	drain1		
2	drain2	1 2	1
3	gate1		3
4	gate2	3 4	5
5	source	[1]	4
			' <u> </u>
			2 sym117

^[1] Connected to flange.

3. Ordering information

Table 3. Ordering information

Type number	er Package					
	Name	Description	Version			
BLF578	-	flanged balanced LDMOST ceramic package; 2 mounting holes; 4 leads	SOT539A			

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Mi	in M	Max	Unit
V_{DS}	drain-source voltage		-	1	110	V
V_{GS}	gate-source voltage		-0).5 +	⊦ 11	V
I _D	drain current		-	8	38	Α
T _{stg}	storage temperature		-6	55 - 1	⊦ 150	°C
Tj	junction temperature		-	2	225	°C

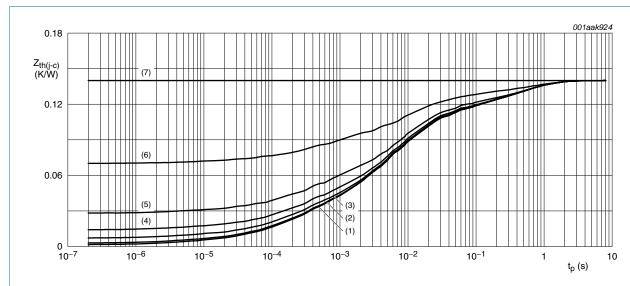
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5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Тур	Unit
$R_{th(j-c)}$	thermal resistance from junction to case	T _j = 150 °C	[1][2] 0.14	K/W
Z _{th(j-c)}	transient thermal impedance from junction to case	T_j = 150 °C; t_p = 100 μs ; δ = 20 %	[3] 0.04	K/W

- [1] T_i is the junction temperature.
- [2] $R_{th(j-c)}$ is measured under RF conditions.
- [3] See Figure 1.



- (1) $\delta = 1 \%$
- (2) $\delta = 2 \%$
- (3) $\delta = 5 \%$
- (4) $\delta = 10 \%$
- (5) $\delta = 20 \%$
- (6) $\delta = 50 \%$
- (7) $\delta = 100 \% (DC)$

Fig 1. Transient thermal impedance from junction to case as function of pulse duration

6. Characteristics

Table 6. DC characteristics

 $T_i = 25$ °C; per section unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 2.5 \text{ mA}$	110	-	-	V
V _{GS(th)}	gate-source threshold voltage	$V_{DS} = 10 \text{ V}; I_D = 500 \text{ mA}$	1.25	1.7	2.25	V
V_{GSq}	gate-source quiescent voltage	$V_{DS} = 50 \text{ V}; I_{D} = 20 \text{ mA}$	8.0	1.3	1.8	V
I _{DSS}	drain leakage current	$V_{GS} = 0 \text{ V}; V_{DS} = 50 \text{ V}$	-	-	2.8	μΑ

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 Table 6.
 DC characteristics ...continued

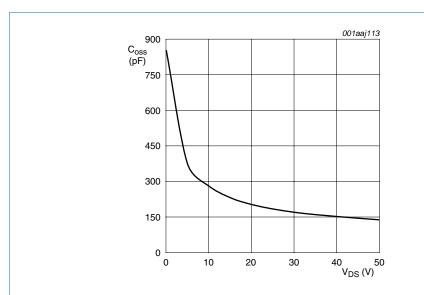
 $T_i = 25$ °C; per section unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
I_{DSX}	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $V_{DS} = 10 \text{ V}$	58	70	-	Α
I_{GSS}	gate leakage current	$V_{GS} = 11 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	280	nΑ
R _{DS(on)}	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 V;$ $I_D = 16.66 A$	-	0.07	-	Ω
C _{rs}	feedback capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 50 \text{ V};$ f = 1 MHz	-	3	-	pF
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 50 \text{ V};$ f = 1 MHz	-	403	-	pF
C _{oss}	output capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 50 \text{ V};$ f = 1 MHz	-	138	-	pF

Table 7. RF characteristics

Mode of operation: pulsed RF; t_p = 100 μ s; δ = 20 %; f = 225 MHz; RF performance at V_{DS} = 50 V; I_{Dq} = 40 mA; T_{case} = 25 °C; unless otherwise specified; in a class-AB production test circuit.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Gp	power gain	$P_L = 1200 \text{ W}$	23	24	25.4	dB
RLin	input return loss	P _L = 1200 W	14	17.5	-	dB
η_{D}	drain efficiency	P _L = 1200 W	68	71	-	%



 $V_{GS} = 0 V$; f = 1 MHz.

Fig 2. Output capacitance as a function of drain-source voltage; typical values per section

6.1 Ruggedness in class-AB operation

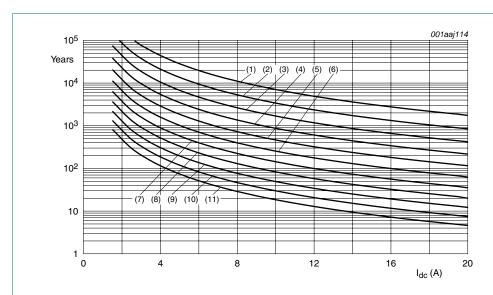
The BLF578 is capable of withstanding a load mismatch corresponding to VSWR = 13 : 1 through all phases under the following conditions: V_{DS} = 50 V; I_{Dq} = 40 mA; P_{L} = 1200 W pulsed; f = 225 MHz.

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7. Application information

7.1 Reliability



TTF (0.1 % failure fraction).

The reliability at pulsed conditions can be calculated as follows: TTF (0.1 %) \times 1/ $\delta.$

- (1) $T_j = 100 \, ^{\circ}C$
- (2) $T_j = 110 \, ^{\circ}C$
- (3) $T_j = 120 \, ^{\circ}C$
- (4) $T_j = 130 \,^{\circ}C$
- (5) $T_j = 140 \, ^{\circ}C$
- (6) $T_j = 150 \, ^{\circ}\text{C}$
- (7) $T_j = 160 \,^{\circ}C$
- (8) $T_j = 170 \, ^{\circ}\text{C}$
- (9) $T_j = 180 \, ^{\circ}C$
- (10) $T_j = 190 \, ^{\circ}C$
- (11) $T_i = 200 \, ^{\circ}C$

Fig 3. BLF578 electromigration (I_D, total device)

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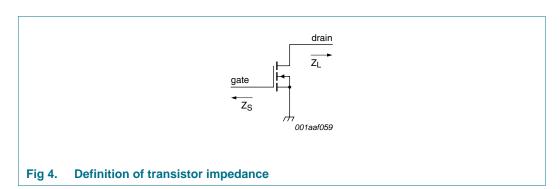
8. Test information

8.1 Impedance information

Table 8. Typical impedance

Simulated Z_S and Z_L test circuit impedances.

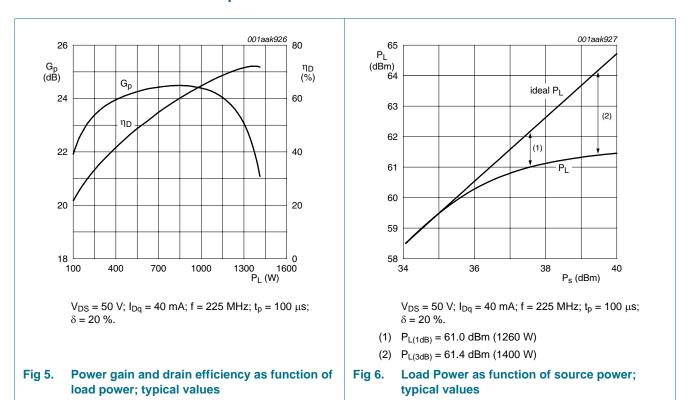
f	Z _S	Z _L
MHz	Ω	Ω
225	3.2 + j2.6	3.7 – j0.2



8.2 RF performance

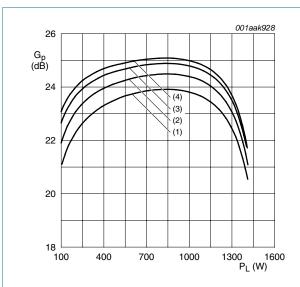
The following figures are measured in a class-AB production test circuit.

8.2.1 1-Tone CW pulsed



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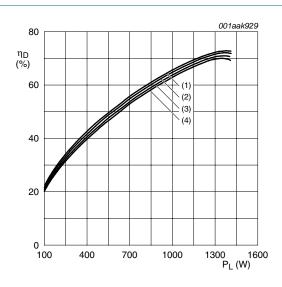
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 V_{DS} = 50 V; f = 225 MHz; t_p = 100 μ s; δ = 20 %.

- (1) $I_{Dq} = 0 \text{ mA}$
- (2) $I_{Dq} = 40 \text{ mA}$
- (3) $I_{Dq} = 80 \text{ mA}$
- (4) $I_{Dq} = 160 \text{ mA}$

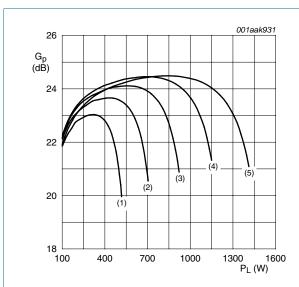
Fig 7. Power gain as a function of load power; typical values



 $V_{DS} = 50 \text{ V}$; f = 225 MHz; $t_p = 100 \text{ }\mu\text{s}$; $\delta = 20 \text{ }\%$.

- (1) $I_{Dq} = 0 \text{ mA}$
- (2) $I_{Dq} = 40 \text{ mA}$
- (3) $I_{Dq} = 80 \text{ mA}$
- (4) $I_{Dq} = 160 \text{ mA}$

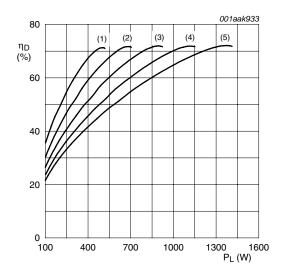
Fig 8. Drain efficiency as a function of load power; typical values



 I_{Dq} = 40 mA; f = 225 MHz; t_p = 100 μ s; δ = 20 %.

- (1) $V_{DS} = 30 \text{ V}$
- (2) $V_{DS} = 35 \text{ V}$
- (3) $V_{DS} = 40 \text{ V}$
- (4) $V_{DS} = 45 \text{ V}$
- (5) $V_{DS} = 50 \text{ V}$

Fig 9. Power gain as a function of load power; typical values



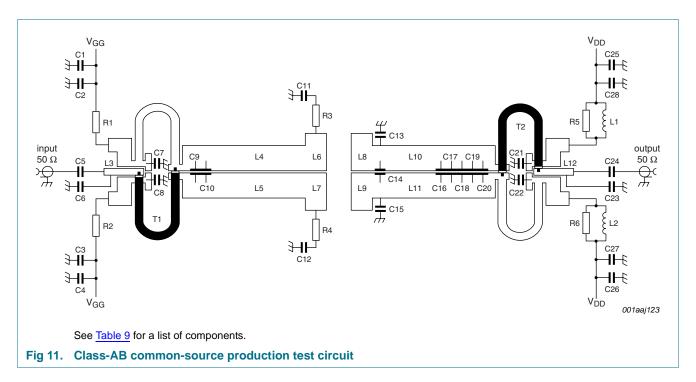
 I_{Dq} = 40 mA; f = 225 MHz; t_p = 100 μ s; δ = 20 %.

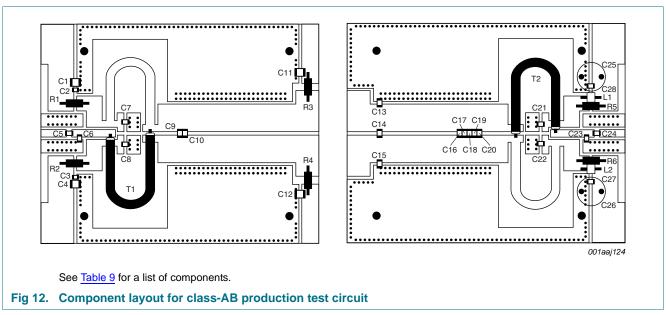
- (1) $V_{DS} = 30 \text{ V}$
- (2) $V_{DS} = 35 \text{ V}$
- (3) $V_{DS} = 40 \text{ V}$
- (4) $V_{DS} = 45 \text{ V}$
- (5) $V_{DS} = 50 \text{ V}$

Fig 10. Drain efficiency as a function of load power; typical values

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8.3 Test circuit





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Table 9. List of components

For production test circuit, see Figure 11 and Figure 12. Printed-Circuit Board (PCB): Rogers 5880; $\varepsilon_r = 2.2$ F/m; height = 0.79 mm; Cu (top/bottom metallization); thickness copper plating = 35 μ m.

Component	Description	Value		Remarks
C1, C2, C11, C12	multilayer ceramic chip capacitor	4.7 μF		TDK4532X7R1E475Mt020U
C2, C3, C27, C28	multilayer ceramic chip capacitor	100 nF		Murata X7R 250 V
C5, C7, C8, C21, C22	multilayer ceramic chip capacitor	1 nF	[1]	
C6	multilayer ceramic chip capacitor	30 pF	[1]	
C9, C10, C13, C15	multilayer ceramic chip capacitor	62 pF	[1]	
C14	multilayer ceramic chip capacitor	36 pF	[1]	
C16, C17	multilayer ceramic chip capacitor	24 pF	[1]	
C18	multilayer ceramic chip capacitor	30 pF	[1]	
C19	multilayer ceramic chip capacitor	27 pF	[1]	
C20	multilayer ceramic chip capacitor	9.1 pF	[1]	
C23	multilayer ceramic chip capacitor	13 pF	[1]	
C24	multilayer ceramic chip capacitor	16 pF	[1]	
C25, C26	electrolytic capacitor	220 μF; 63 V		
L1, L2	3 turns 1 mm copper wire	D = 2 mm; length = 3 mm		
L3, L12	stripline	-		(L \times W) 15 mm \times 2.4 mm
L4, L5, L10, L11	stripline	-		(L \times W) 47 mm \times 10 mm
L6, L7, L8, L9	stripline	-		(L \times W) 8 mm \times 15 mm
R1, R2	metal film resistor	2 Ω; 0.6 W		
R3, R4	metal film resistor	20 Ω; 0.6 W		
R5, R6	metal film resistor	1 Ω; 0.6 W		
T1, T2	semi rigid coax	50Ω ; 58 mm		EZ-141-AL-TP-M17

^[1] American Technical Ceramics type 100B or capacitor of same quality.

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9. Package outline

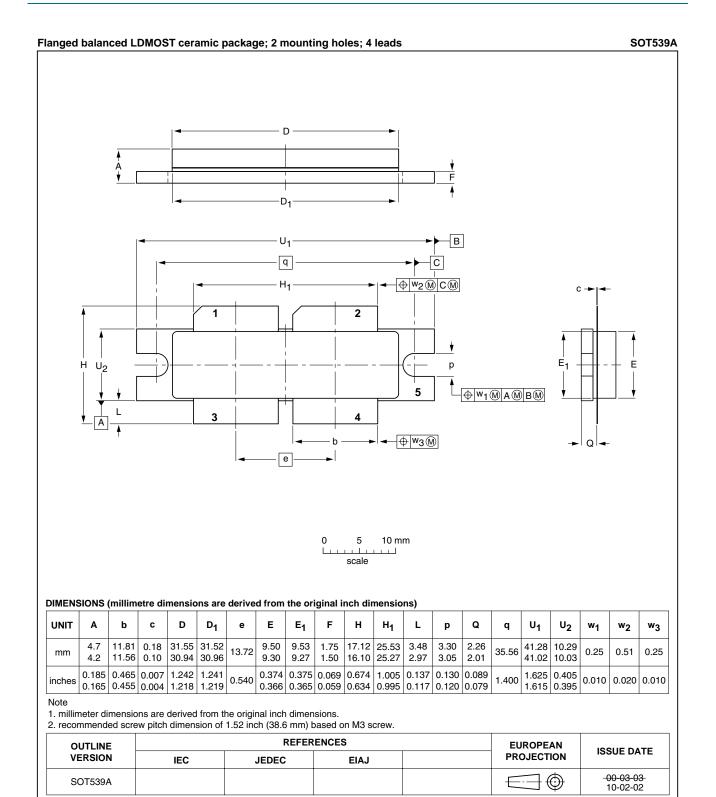


Fig 13. Package outline SOT539A

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10. Abbreviations

Table 10. Abbreviations

Acronym	Description
CW	Continuous Wave
EDGE	Enhanced Data rates for GSM Evolution
GSM	Global System for Mobile communications
HF	High Frequency
LDMOS	Laterally Diffused Metal-Oxide Semiconductor
LDMOST	Laterally Diffused Metal-Oxide Semiconductor Transistor
RF	Radio Frequency
TTF	Time To Failure
VSWR	Voltage Standing-Wave Ratio

11. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes	
BLF578_2	20100204	Product data sheet	-	BLF578_1	
Modifications:	Table 1 on p	age 1: added information for 0	CW performance.		
	 Section 1 on 	page 1: changed typical value	e of η _D .		
	 <u>Table 4 on page 2</u>: changed maximum value of I_D. 				
	Table 5 on page 3: changed value of R _{th(i-c)} .				
	• <u>Table 5 on page 3</u> : added information about Z _{th(j-c)} .				
	• Figure 1 on	page 3: added figure.			
	• Table 6 on p	age 3: added values vor V _{GSq}			
	• Table 6 on p	age 3: changed typical value of	of I _{DSX} .		
	 Table 7 on page 4: changed some values. 				
	• Section 8.2.	1 on page 6: changed some g	raphs.		
BLF578_1	20081211	Objective data sheet	-	-	

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12. Legal information

12.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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